

InGaN–GaN Multiple Quantum Wells for Green LEDs on Si

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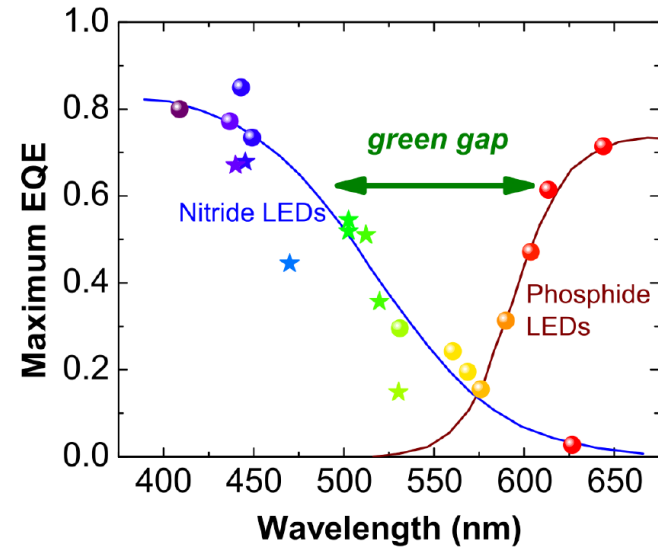
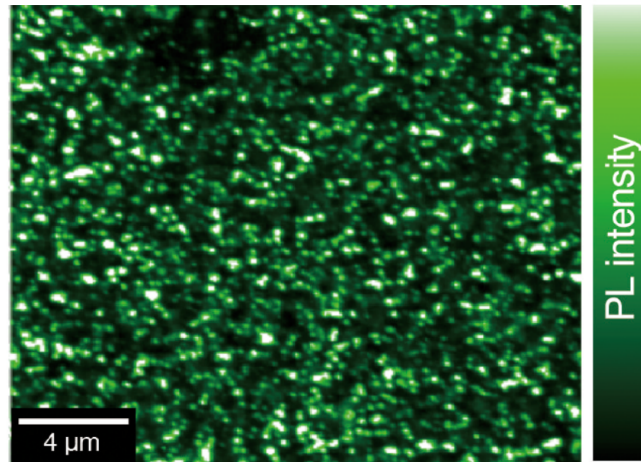
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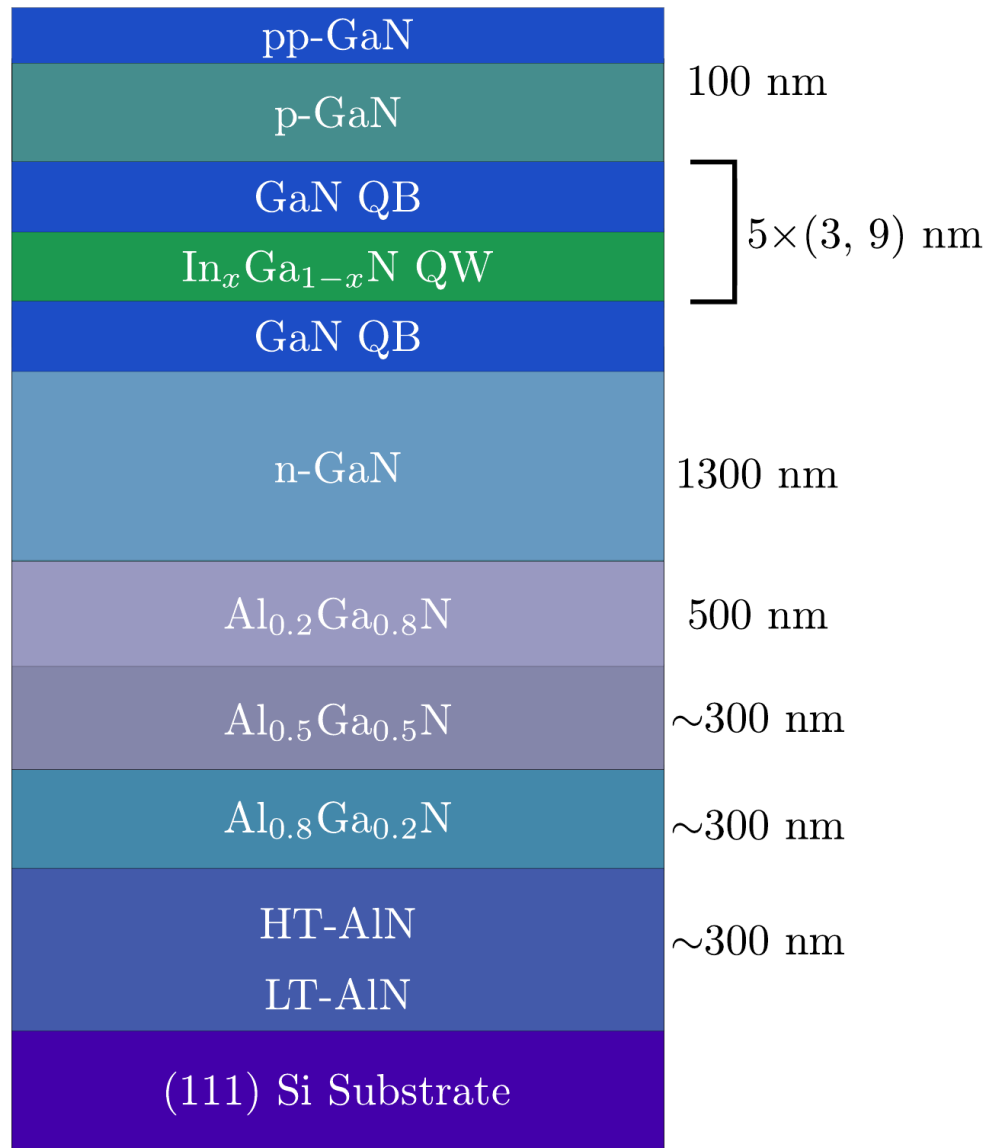
Green InGaN–GaN Light Emitting Diodes



- ▶ III-N direct bandgaps cover UV to IR wavelengths
- ▶ $\text{In}_x\text{Ga}_{1-x}\text{N}$ with $x \approx 20\%$ for direct green emission
- ▶ Complex alloy picture: growth and misfit defects, phase separation, spontaneous and piezoelectric polarization...

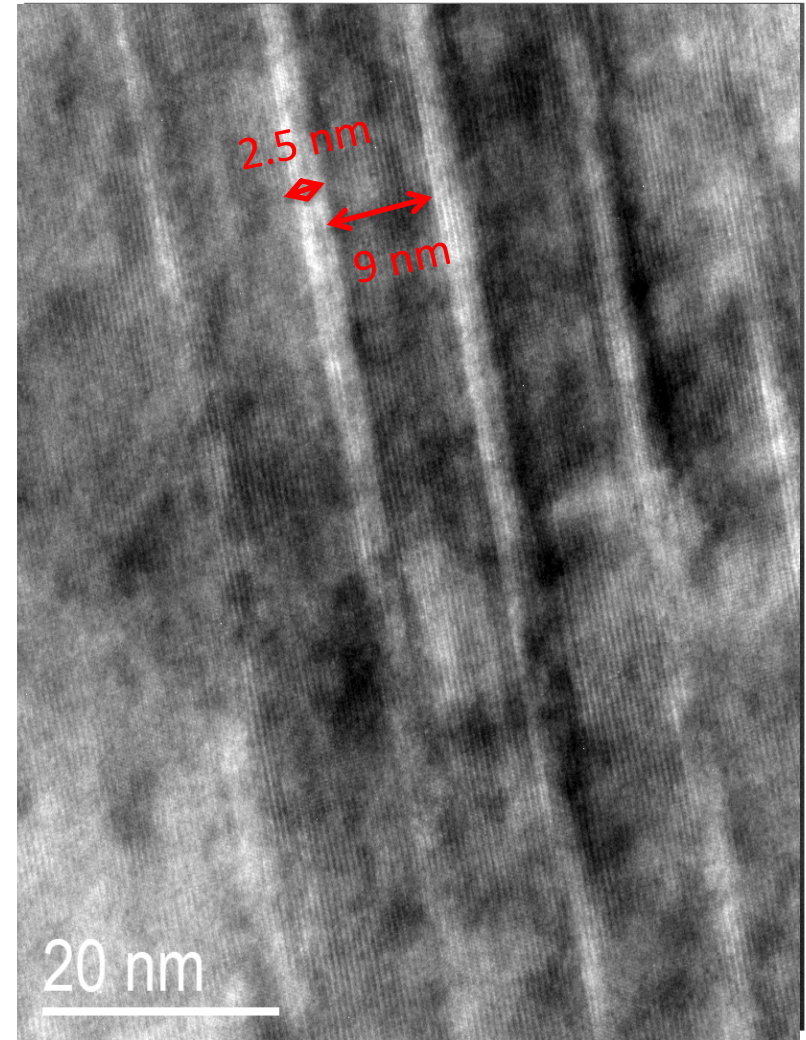
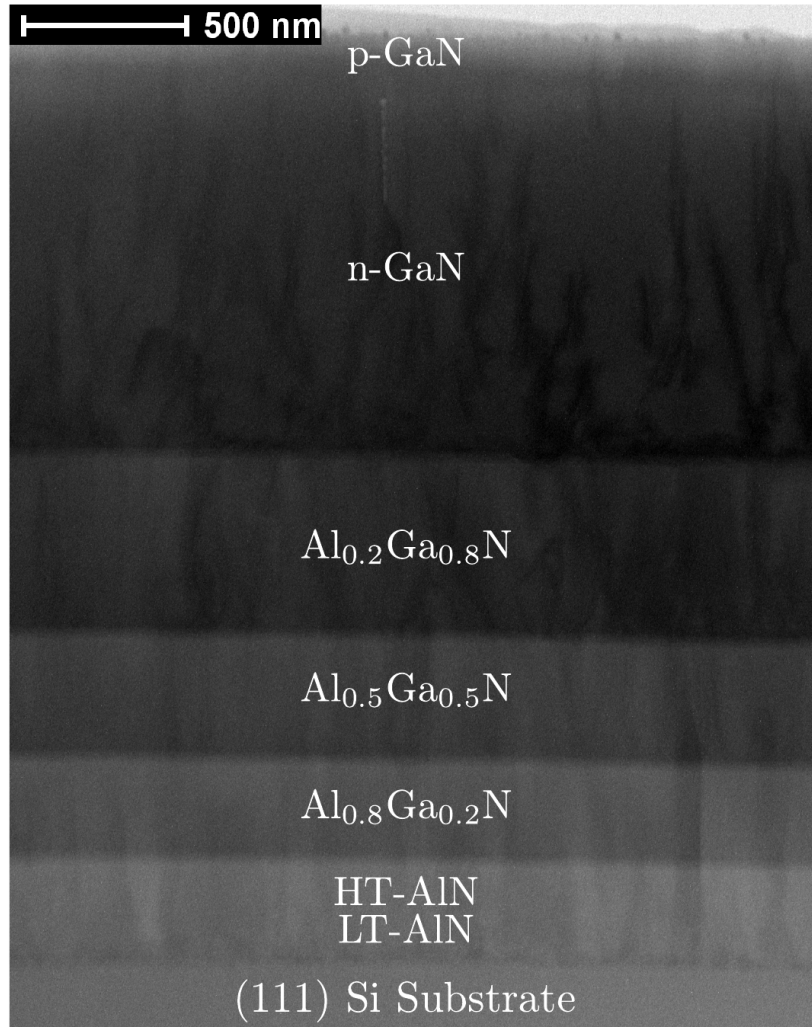
Left figure adapted from Jeong, H. et al. in *Scientific Reports* **Mar. 2015**, 5, 9373. Right figure from Auf der Maur, M. et al. *Physical Review Letters* **Jan. 2016**, 116, 027401.

Green Multiple Quantum Well LED on Si

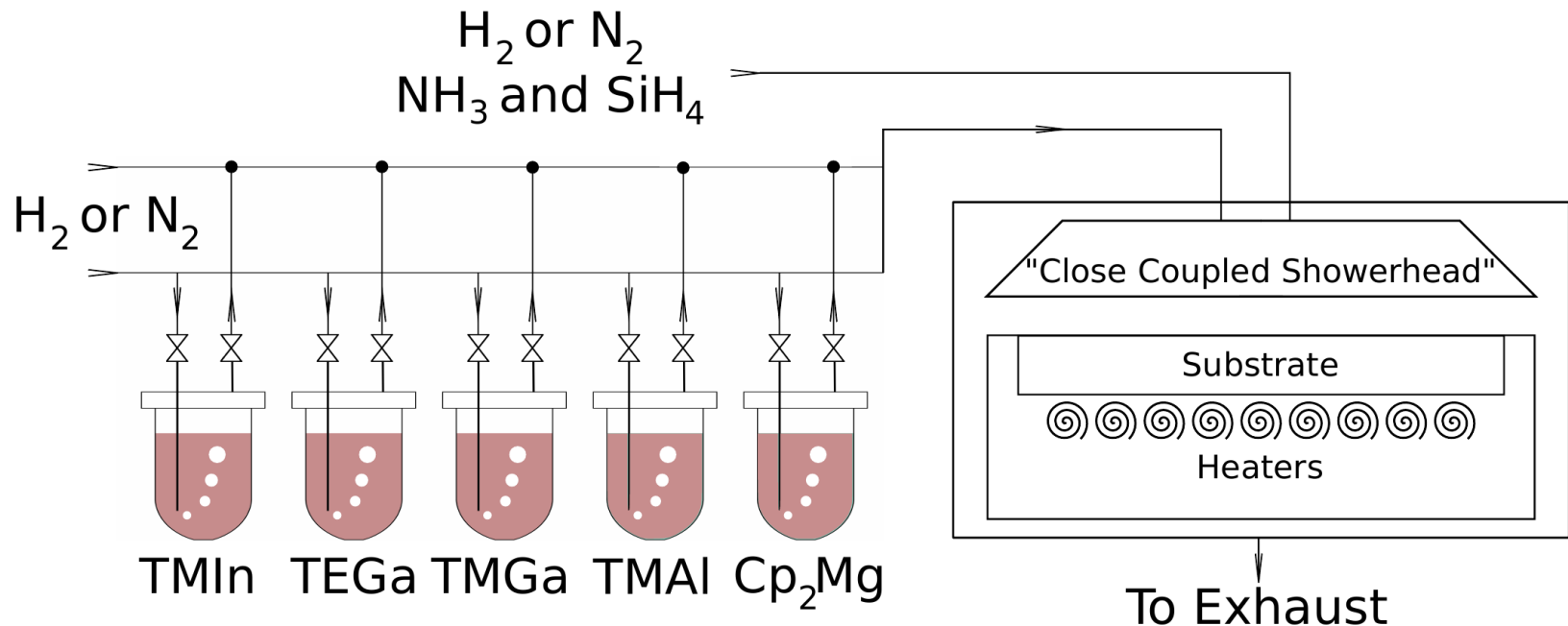


- ▶ GaN on Si: lattice mismatch, thermal mismatch, Ga etchback
- ▶ Pre-existing buffer structure for GaN on Si in SNF, adopted for GaN MQW LED on Si growth
- ▶ Not wafer scale without optimization, but $100 \mu\text{m}$ to $1000 \mu\text{m}$ between observed cracks.

General Result by Transmission Electron Microscopy

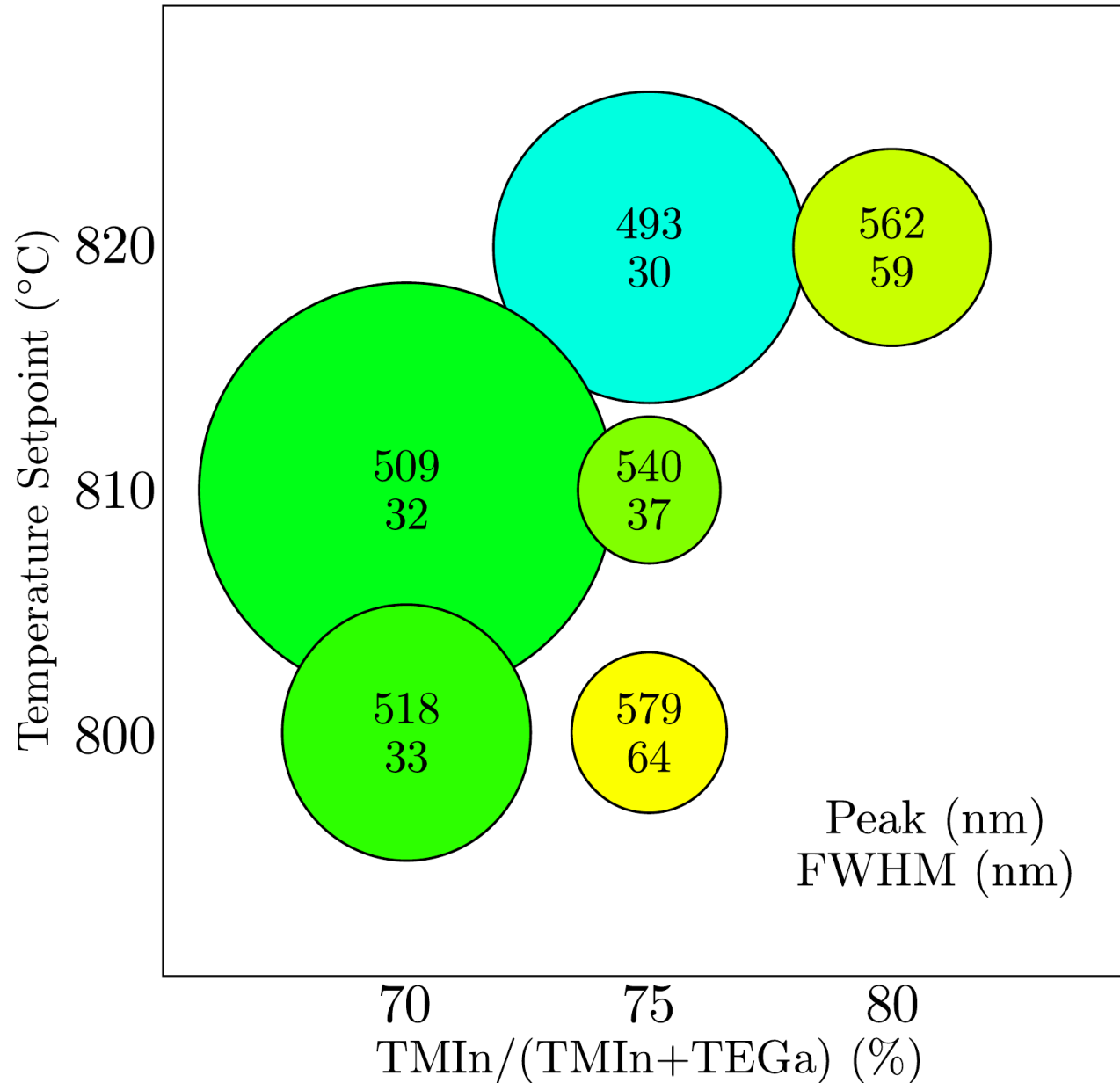


Organometallic Chemical Vapor Deposition (MOCVD)

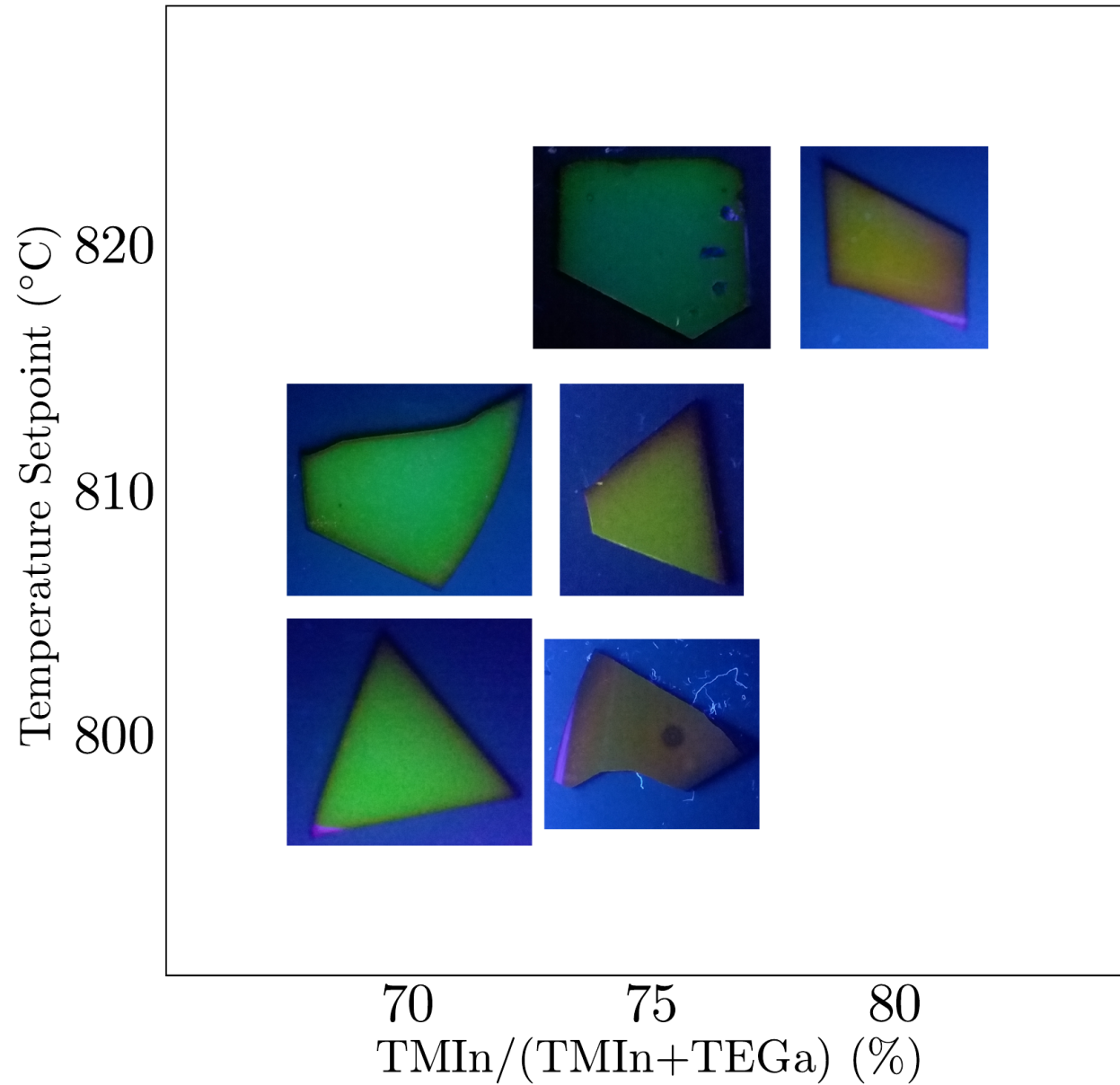


- ▶ Thin film deposition process for large-area, nm-scale, epitaxial thin films
- ▶ Precursors pyrolyze on heated growth substrate at 700°C to 1100°C (for our experiments)
- ▶ Heavy use in industrial production of LEDs

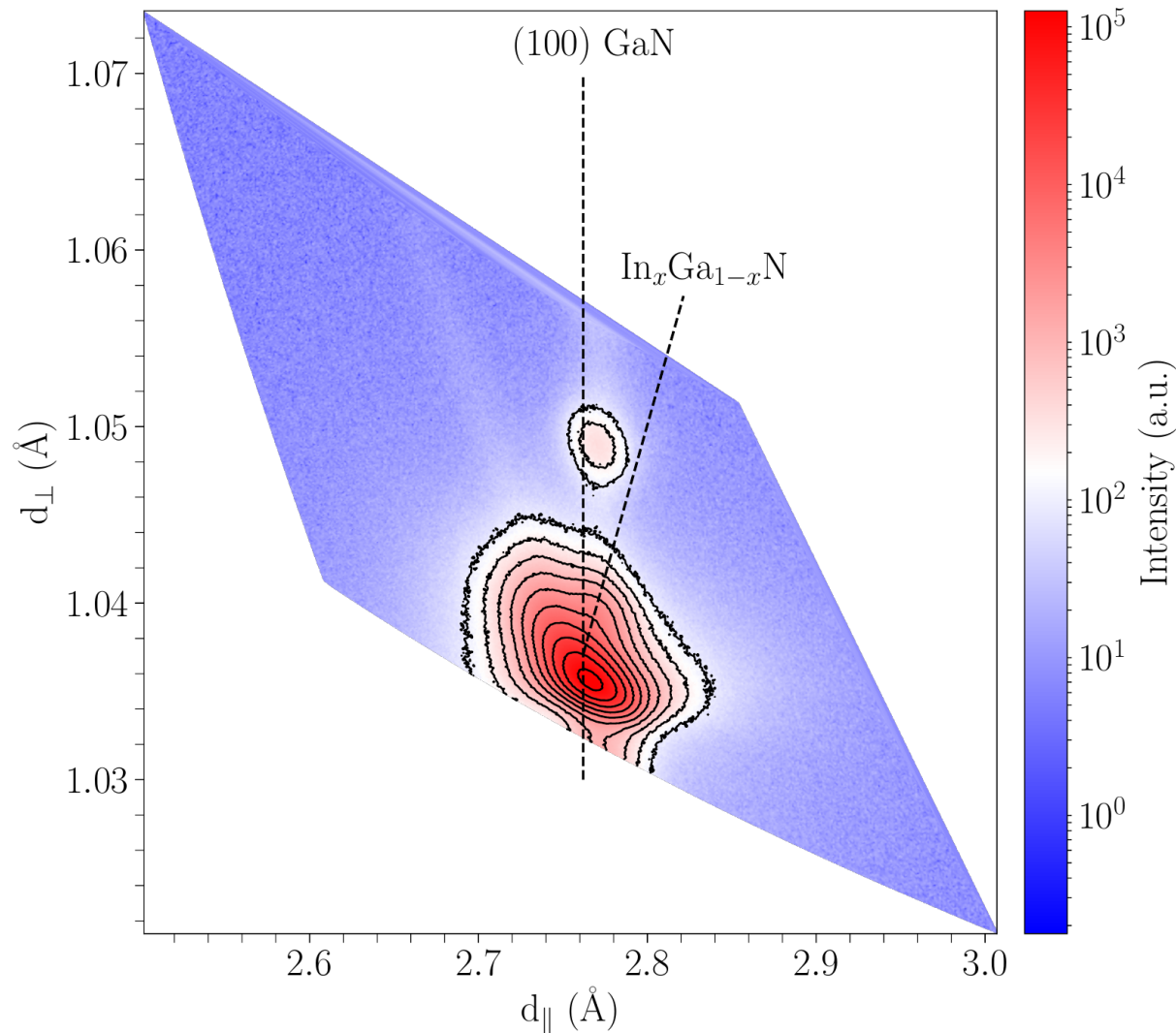
T-TMIn/III vs λ Space for MQW LED Structures



Specimen Photoluminescence at 365 nm

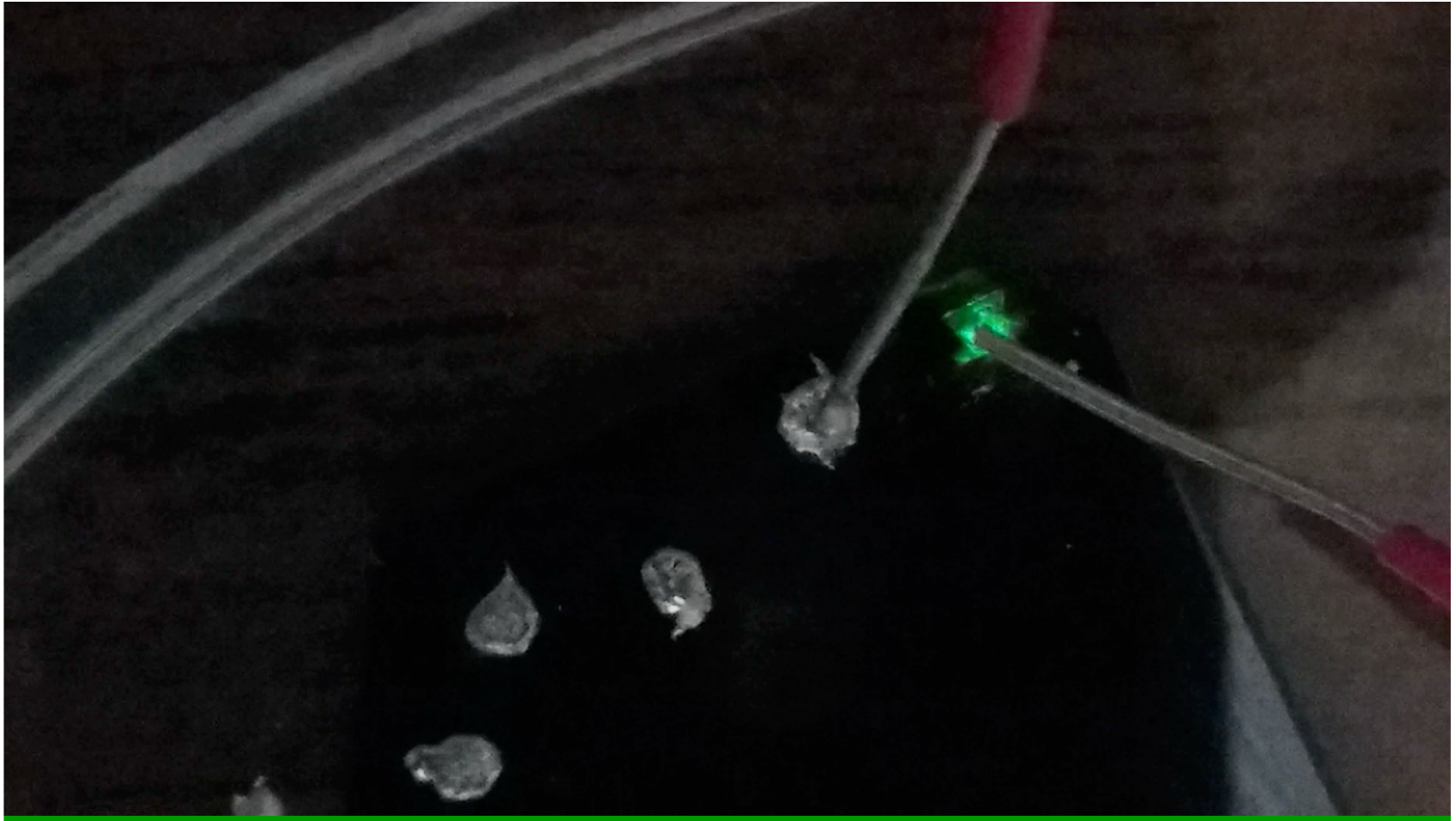


Incoherent Strain and X-ray Diffraction, $\bar{1}05$

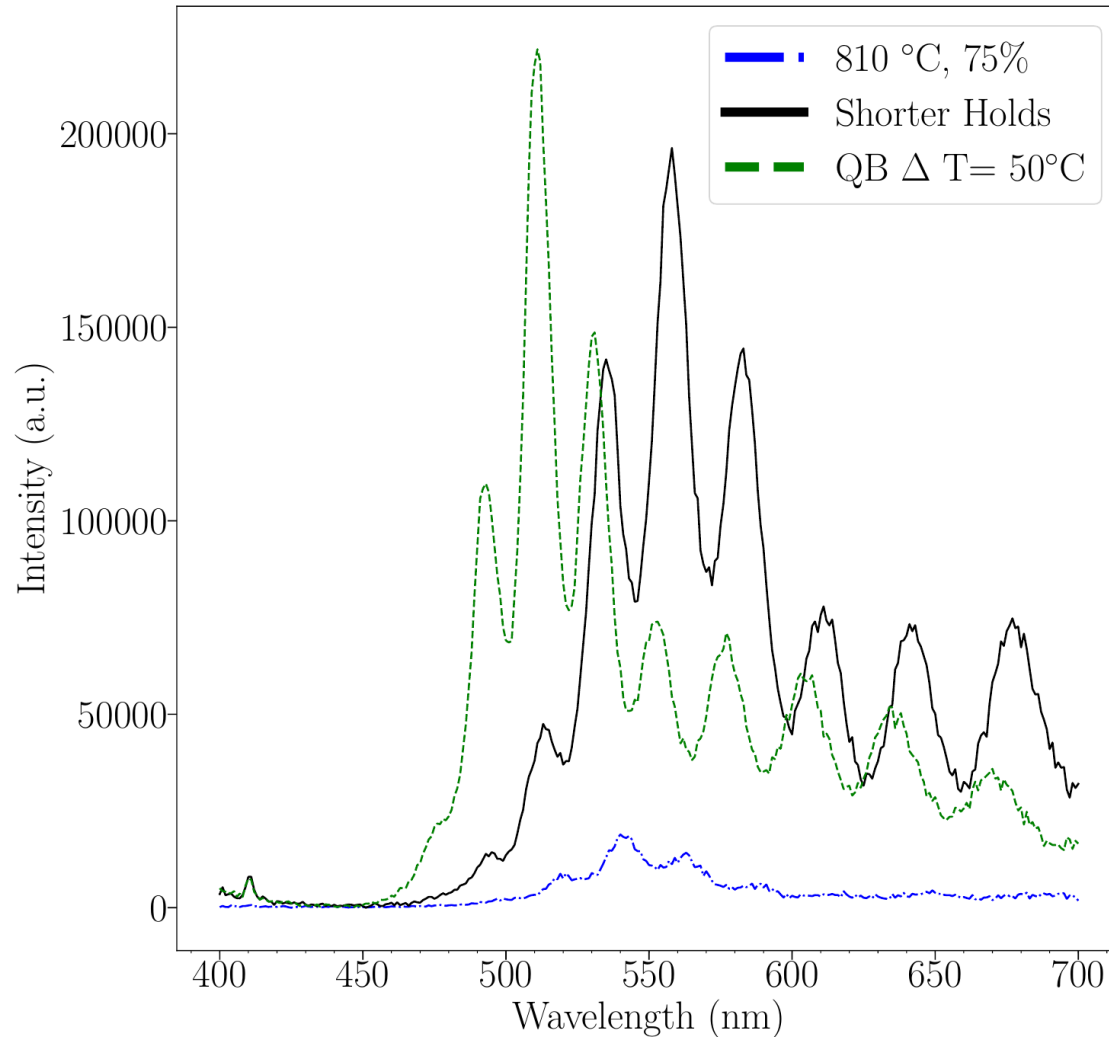


- ▶ 2/3 InGa_N growth time + all measured specimens incoherent
- ▶ (002) maps prove GaN-InGa_N in-plane lattice mismatch

Qualitative Electroluminescence



Additional Experiments

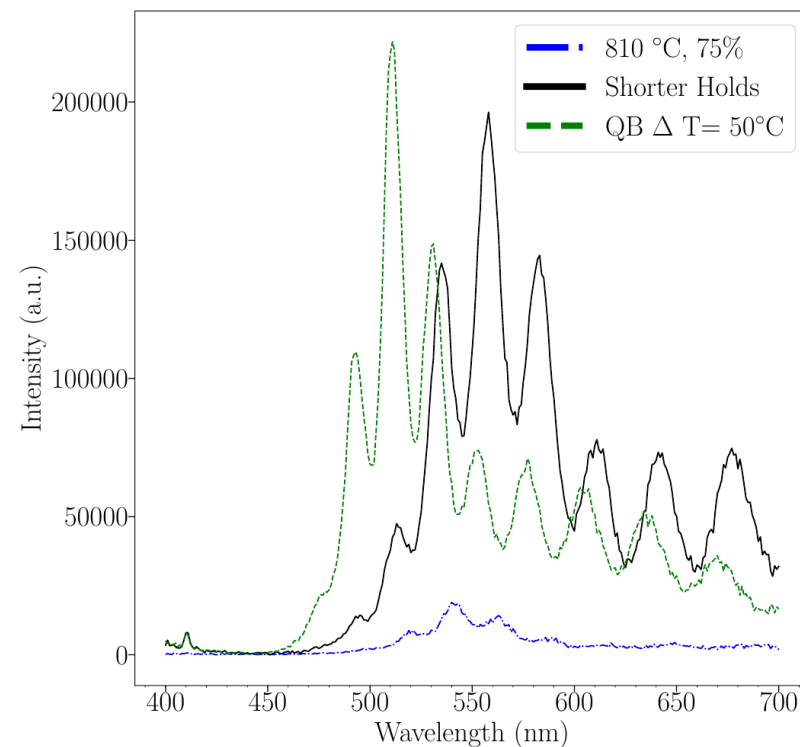
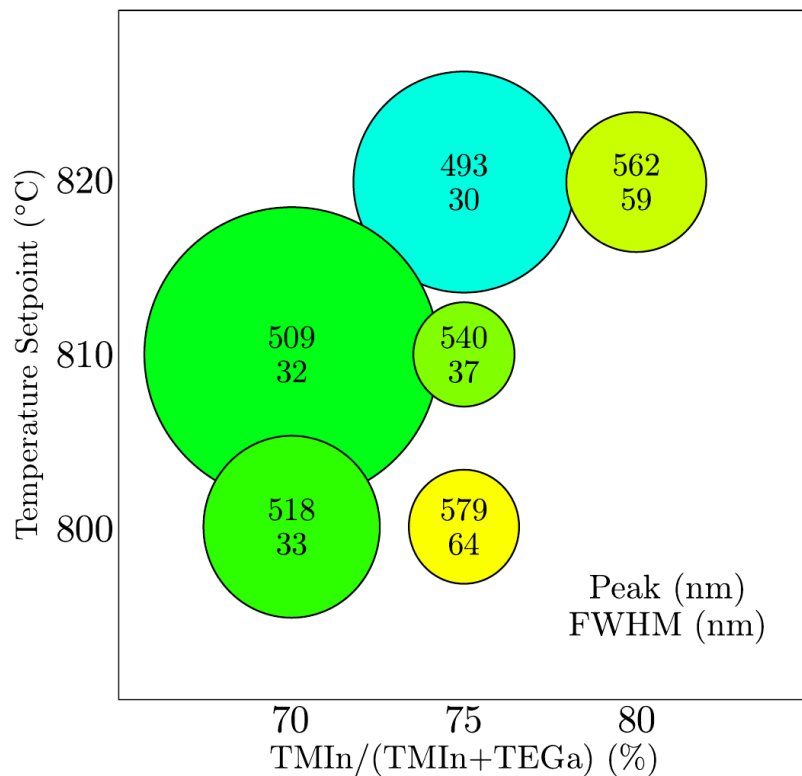


- ▶ Reducing hold times at interfaces and higher GaN quantum barrier growth expected to improve quality
- ▶ Initial experiments indicate improved photoluminescence

Lessons Learned

- ▶ The X'Pert 2 diffractometer will lie to you about reciprocal space map times. $3^\circ \times 3^\circ$ RSMs at 0.01° resolution takes 3 hours, not 100.
- ▶ Choose stiff AFM tips for hard specimens. This reduced AFM errors for us.
- ▶ X-ray superlattice fringes exist and we should look for them.
- ▶ Gallium bubbles in TEM, something we've yet to address.

Conclusions



- ▶ Established initial process parameters for green MQW on Si LED recipes
- ▶ Characterized specimens using SEM, XRD, AFM, PL, and two in TEM.
- ▶ Recipes may be improved upon in future optimizations

Thank you!

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- ▶ Xiaoqing, Michael Grundmann, and Dong Lee, for everything
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- ▶ Juliet Jamtgaard for help with TEM
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